

On BTI aging rejuvenation in memory address decoders

Gürsoy, Cemil Cem; Kraak, Daniel; **Ahmed, Faisal**; Taouil, Mottaqiallah; **Jenihhin, Maksim**; Hamdioui, Said 2022 IEEE 23rd Latin American Test Symposium, LATS 2022 2022 / Code 184360 <https://doi.org/10.1109/LATS57337.2022.9936940>

Software-based mitigation for memory address decoder aging

Kraak, D. H. P.; **Gürsoy, Cemil Cem**; **Jenihhin, Maksim**; **Raik, Jaan** LATS 2019 : 20th IEEE Latin American Test Symposium : Santiago, Chile, March 11th - 13th 2019 2019 / 6 p. : ill <https://doi.org/10.1109/LATW.2019.8704595>